

Si_FDS1b2_mask10_15ago2024.xrdml

Report

Created on: 03/09/2024 14:43:44

Operator: LSCnM2020_pcRaman

File

File name: D:\LSCnM_UFSC\dados_LDRX_UFSC\Padroes\Si_VM\Si_FDS1b2_mask10_15ago2

Checksum: bd98bfa2e356b1d6bd0d31487e53d502

File size 106344
(bytes):

Time stamp

Started: 15/08/2024 07:17:00

Finished: 15/08/2024 09:06:02

Total time 01:49:02
(h:m:s):

Comment

Configuration=PoXcelSpinner1, Owner=Carlos, Creation date=14/11/2019 15:05:29
Goniometer=PW3050/60 (Theta/Theta); Minimum step size 2Theta:0,001; Minimum step size Omega:
Sample stage=Reflection-Transmission Spinner PW3064/60; Minimum step size Phi:0,1
Diffractometer system=XPERT-PRO
Measurement program=MedePadroes, Owner=Carlos, Creation date=30/3/2022 15:20:44
Batch program=mede Padroes, Owner=Carlos, Creation date=30/3/2022 15:23:09

Status

Completed

Sample

Sample To be analyzed
type:

Sample ID: Si NIST

Sample na cav do ZB gde coM faca 1a div e spun 4s
name:

Prepared by: Grupo LSCnM

Measurement type

Repeated scan (3 times)

Used wavelength

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Intended wavelength type: $K\alpha$
 $K\alpha_1$ (Å): 1,540598
 $K\alpha_2$ (Å): 1,544426
 $K\alpha_2/K\alpha_1$ intensity ratio: 0,50
 $K\alpha$ (Å): 1,541874
 $K\beta$ (Å): 1,392250

Incident beam path

Radius (mm): 240,0

X-ray tube

Name: PW3373/00 Cu LFF DK423121

Anode material: Cu

Voltage (kV): 45

Current (mA): 40

Focus

Focus type: Line

Length (mm): 12,0

width (mm): 0,4

Take-off angle (°): 6,0

Soller slit

Name: Soller 0.04 rad.

Opening (rad.): 0,04

Mask

Name: Inc. Mask Fixed 10 mm (MPD/MRD)

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Width 6,60
(mm):

Anti-scatter slit

Name: Slit Fixed 1°
Type: Fixed
Height 1,52
(mm):

Divergence slit

Name: Slit Fixed 1/2°
Distance 140
to sample
(mm):
Type: Fixed
Height 0,76
(mm):

Sample movement

Movement type: Spinning
Rotation 4,0
time (s):

Diffracted beam path

Radius 240,0
(mm):

Anti-scatter slit

Name: AS Slit 5.0 mm (X'Celerator)
Type: Fixed
Height 5,00
(mm):

Soller slit

Name: Large Soller 0.04 rad.
Opening 0,04
(rad.):

Filter

Name: Nickel

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Thickness 0,020

(mm):

Material: Ni

Detector

Name: X'Celerator

Type: RTMS detector

PHD - 41,5

Lower

level (%):

PHD - 98,0

Upper

level (%):

Mode: Scanning

Active 2,122

length (°):

Source

Created by: Administrador

Application X'Pert Data Collector

SW: vs. 2.2c

Instrument XPERT-PRO

control SW: vs. 2.2D

Instrument 0000000011026311

ID:

Comment

medida de Padroes (Si, Al₂O₃, CeO₂, Y₂O₃)

Sample mode

Reflection

Scan 1

Start time 15/08/2024 07:17:00

stamp:

End time 15/08/2024 07:53:14

stamp:

Scan axis: Gonio

Scan range 15,0000 - 90,0002

(°):

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Step size (°): 0,0084

No. of

points:

Scan mode: Continuous

Phi (°): 42,3

Counting

time (s):

Scan 2

Start time 15/08/2024 07:53:22

stamp:

End time 15/08/2024 08:29:38

stamp:

Scan axis: Gonio

Scan range 15,0000 - 90,0002

(°):

Step size (°): 0,0084

No. of

points:

Scan mode: Continuous

Phi (°): 42,3

Counting

time (s):

Scan 3

Start time 15/08/2024 08:29:47

stamp:

End time 15/08/2024 09:06:02

stamp:

Scan axis: Gonio

Scan range 15,0000 - 90,0002

(°):

Step size (°): 0,0084

No. of

points:

Scan mode: Continuous

Phi (°): 42,3

Counting

time (s):

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